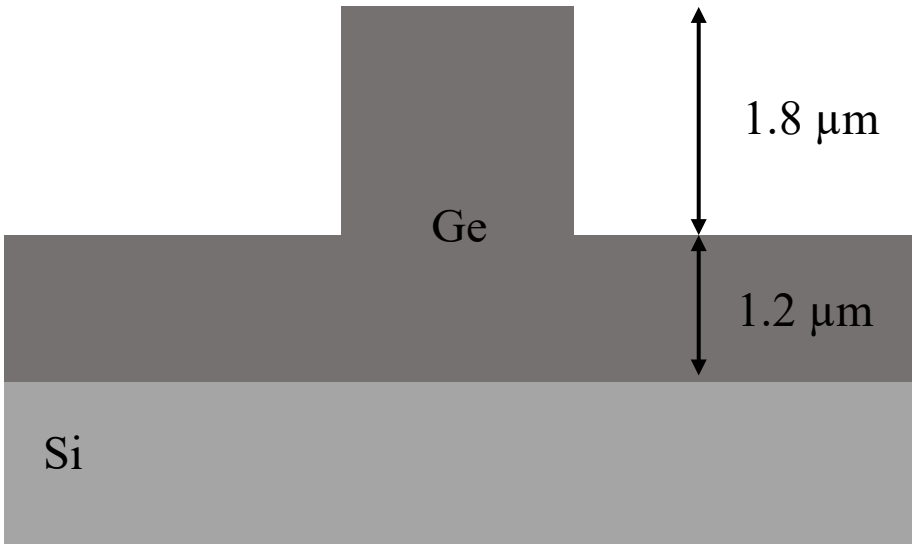
CORNERSTONE STANDARD COMPONENTS LIBRARY

Preface

In this document, we summarized the up-to-date designs and their measurement results of our CORNERSTONE standard components on Germanium-on-Silicon (Ge-on-Si) platforms, at the same time we are optimizing the current designs, adding in new designs, and gathering more measurement results. Most of the dimensions are given in this documents, whilst a few of them are not. Thus, please use this document together with out up-to-date GDS library with can be downloaded at https://www.cornerstone.sotonfab.co.uk/design-rules/ .

List of Contents

- **Wavelength: 3800 nm**
- **Platform: Ge-on-Si**
- **RIB WAVEGUIDE**



Ge-on-Si_3800 nm_TE_Rib_Waveguide

Platform:	Ge-on-Si
Wavelength:	3800 nm
Etching depth:	1.8 µm (Rib design)
Polarization:	TE
Cell name in GDS lib:	Ge_on_Si_3800nm_TE_RIB_Waveguide

Ge-on-Si_3800 nm_TE_Rib_90_Degree_Bend

Platform:	Ge-on-Si
Wavelength:	3800 nm
Etching depth:	1.8 µm (Rib design)
Polarization:	TE
Cell name in GDS lib:	Ge_on_Si_3800nm_TE_RIB_90_Degree_Bend